

#### **IEC QUALITY ASSESSMENT SYSTEM (IECQ)**

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

# Schedule of Scope to Certificate of Conformity Approved Process

IECQ Certificate No.: IECQ-P ULTW 16.0003-01

**CB Certificate No.: T1107-1** 

Schedule Number: IECQ-P ULTW 16.0003-01-S Rev No.: 1 Revision Date: 2018/09/20 Page 1 of 3

### **Appendix-1** (T1107-1) **Schedule of Scope to Certificate of Approval**

Description test	Standard	Remarks
SEM	T-SEM-3	By customer requirement
TEM-EELS	Т-ТЕМ-3	By customer requirement
EDS	T-SEM-3, T-TEM-3	By customer requirement
FIB	T-FIB-3	By customer requirement
Liquid Cell	Т-ТЕМ-3	By customer requirement
SIMS	T-SIM-3	By customer requirement
AFM	T-SIM-3	By customer requirement
SRP	T-SIM-3	By customer requirement
Alpha step	T-SIM-3	By customer requirement
XRD	T-SIM-3	By customer requirement
XPS	T-SIM-3	By customer requirement
X-Ray	T-EFA-3	By customer requirement
EMMI	T-EFA-3	By customer requirement
EMMI-InGaAs	T-EFA-3	By customer requirement

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OBIRCH	T-EFA-3	By customer requirement
C-AFM	T-EFA-3	By customer requirement
SCM	T-SIM-3	By customer requirement
Scanning Acoustic Tomography	T-EFA-3	By customer requirement
Optical Microscope	T-OMI-3	By customer requirement
3D Optical Microscope	T-LAB-3	By customer requirement
Optical Profiler	T-SIM-3	By customer requirement
IC Layout Imaging	T-OMI-3	By customer requirement
Circuitry analysis	T-OMI-3	By customer requirement
Auger	T-SIM-3	By customer requirement
THEMOS	T-EFA-3	By customer requirement
TDR	T-LAB-3	By customer requirement
3D X-Ray	T-EFA-3	By customer requirement
Latch-up	JEDEC78	Or customer specified test
нвм	JS-001	Or customer specified test
ММ	JS-001	Or customer specified test
CDM	JS-002	Or customer specified test

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ESD Gun	IEC 61000-4-2	Or customer specified test
TLP	ESDA	Or customer specified test
EOS	IEC 61000-4-5	Or customer specified test
Wire Bonding	NA	By customer requirement
IC Package	NA	By customer requirement
Pull and shear test	MIL-STD-883J method 2011.9 MIL-STD-883J method 2023.7 AEC-Q100-001 EIA/JESD22-B116 JESD22-B117	Or customer specified test

Technical Reviewer of DQS: Michael Chan Date: Sep. 6, 2018

US-NAI, ECCC T.R.C.C. sign:

US-NAI, ECCC T.R.C.C. sign:

Date: Sep. 10, 2018



